### **STD4N90K5**



# N-channel 900 V, 1.90 Ω typ.,3 A MDmesh™ K5 Power MOSFET in a DPAK package

Datasheet - production data

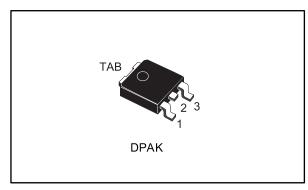
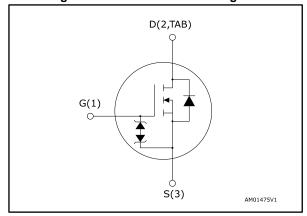


Figure 1: Internal schematic diagram



### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD
STD4N90K5	900 V	2.10 Ω	3 A

- Industry's lowest R<sub>DS(on)</sub> x area
- Industry's best FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

### **Applications**

• Switching applications

### **Description**

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

**Table 1: Device summary** 

Order code	Marking	Marking Package	
STD4N90K5	4N90K5	DPAK	Tape and reel

Contents STD4N90K5

## Contents

1	Electric	al ratings	3
2	Electric	al characteristics	4
	2.1	Electrical characteristics (curves)	6
3	Test cir	cuits	8
4	Packag	e information	9
	4.1	DPAK package information	9
	4.2	DPAK packing information	12
5	Revisio	n history	14

STD4N90K5 Electrical ratings

## 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
Vgs	Gate-source voltage	± 30	V	
$I_D$	Drain current (continuous) at T <sub>C</sub> = 25 °C	3	Α	
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C 1.9			
I <sub>D</sub> <sup>(1)</sup>	Drain current (pulsed)	12	Α	
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	60	W	
dv/dt (2)	Peak diode recovery voltage slope	4.5		
dv/dt (3)	MOSFET dv/dt ruggedness	50 V		
Tj	Operating junction temperature range	55 to 150		
T <sub>stg</sub>	Storage temperature range	- 55 to 150 °C		

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-pcb</sub> <sup>(1)</sup>	Thermal resistance junction-pcb	50	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient	62.5	°C/W

#### Notes

**Table 4: Avalanche characteristics** 

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (pulse width limited by T <sub>jmax</sub> )	1	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	160	mJ

<sup>&</sup>lt;sup>(1)</sup>Pulse width limited by safe operating area

 $<sup>^{(2)}</sup>I_{SD} \leq 3$  A, di/dt  $\leq$  100 A/ $\mu$ s; VDS peak < V(BR)DSS, VDD = 450 V.

 $<sup>^{(3)}</sup>V_{DS} \le 720 \ V$ 

 $<sup>^{(1)}\!</sup>When$  mounted on FR-4 board of 1 inch², 2oz Cu, t < 10 s.

Electrical characteristics STD4N90K5

### 2 Electrical characteristics

T<sub>C</sub> = 25 °C unless otherwise specified

Table 5: On/off-state

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	900			V
		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 900 V			1	μΑ
I <sub>DSS</sub>	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 900 \text{ V}$ $T_{C} = 125 \text{ °C}^{(1)}$			50	μΑ
I <sub>GSS</sub>	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			±10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DD} = V_{GS}$ , $I_D = 100 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 1.5 \text{ A}$		1.90	2.10	Ω

#### Notes:

**Table 6: Dynamic** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	173	-	pF
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$ $V_{GS} = 0 \text{ V}$	-	17.9	-	pF
Crss	Reverse transfer capacitance	VG3 - 0 V	-	1	-	pF
Co(tr) <sup>(1)</sup>	Equivalent capacitance time related	V <sub>DS</sub> = 0 to 720 V,	-	29	-	pF
C <sub>o(er)</sub> <sup>(2)</sup>	Equivalent capacitance energy related	V <sub>GS</sub> = 0 V	-	11	-	pF
Rg	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> = 0 A	-	15.5	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 720 V, I <sub>D</sub> = 3 A	-	5.3	-	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V	-	1.45	-	nC
$Q_{gd}$	Gate-drain charge	(see Figure 15: "Test circuit for gate charge behavior")	-	2.8	-	nC

#### Notes:

<sup>&</sup>lt;sup>(1)</sup> Defined by design, not subject to production test.

 $<sup>^{(1)}</sup>$  Time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

 $<sup>^{(2)}</sup>$  Energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 7: Switching times

Table 11 Children 19 times						
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 450 V, I <sub>D</sub> = 1.50 A,	ı	10.5	1	ns
tr	Rise time	$R_G = 4.7 \Omega$	ı	11.8	ı	ns
t <sub>d(off)</sub>	Turn-off delay time	V <sub>GS</sub> = 10 V (see <i>Figure 14: "Test</i>	ı	26.4	ı	ns
t <sub>f</sub>	Fall time	circuit for resistive load switching times" and Figure 19: "Switching time waveform")	-	25.5	-	ns

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		3	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		12	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 3 A, V <sub>GS</sub> = 0 V	-		1.5	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 3 \text{ A}, \text{ di/dt} = 100$	-	289		ns
Qrr	Reverse recovery charge	A/µs,V <sub>DD</sub> = 60 V (see <i>Figure 16: "Test</i>	-	1.56		μC
I <sub>RRM</sub>	Reverse recovery current	circuit for inductive load switching and diode recovery times")	-	10.8		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 3 A, di/dt = 100 A/µs	-	494		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$ (see <i>Figure 16: "Test</i>	-	2.45		μC
I <sub>RRM</sub>	Reverse recovery current	circuit for inductive load switching and diode recovery times")	-	9.9		Α

#### Notes:

Table 9: Gate-source Zener diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}, I_{D} = 0 \text{ A}$	30	-	-	V

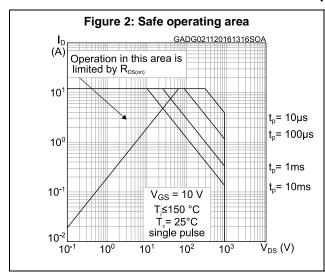
The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

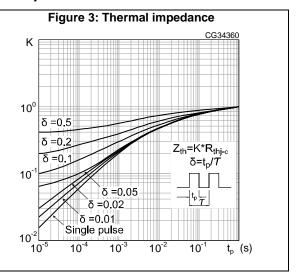


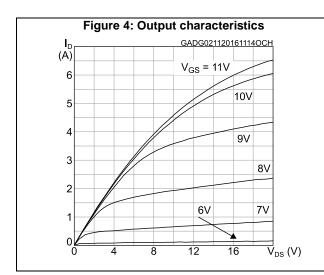
<sup>&</sup>lt;sup>(1)</sup>Pulse width limited by safe operating area

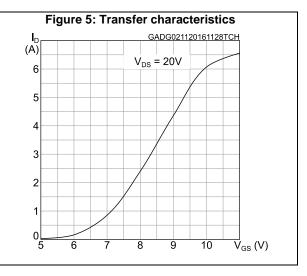
 $<sup>^{(2)}</sup>$ Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

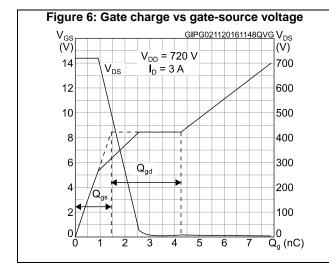
# 2.1 Electrical characteristics (curves)

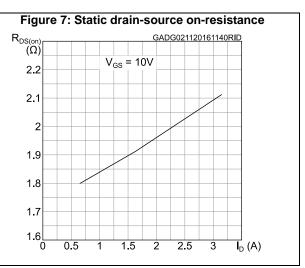












STD4N90K5 Electrical characteristics

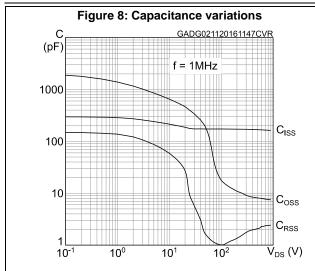
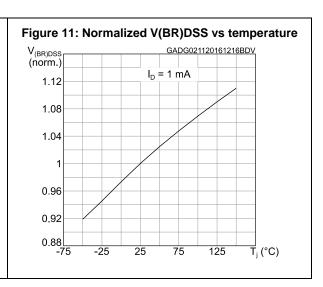
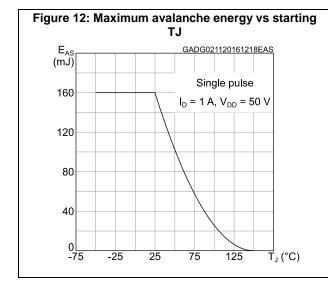
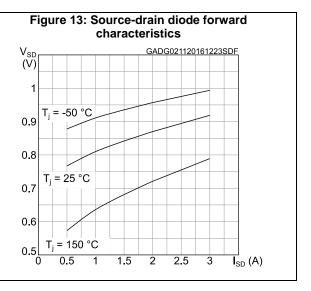


Figure 10: Normalized on-resistance vs temperature  $R_{DS(on)}$  (norm.)  $V_{GS} = 10 \text{ V}$   $V_{GS} = 10$ 







**Test circuits** STD4N90K5

#### 3 **Test circuits**

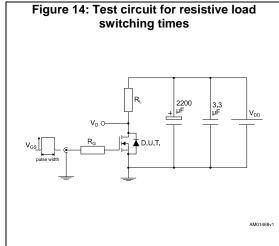


Figure 15: Test circuit for gate charge behavior RL I<sub>G</sub>= CONST 100 Ω  $2.7 \ k\Omega$ 47 kΩ AM01469v10

Figure 16: Test circuit for inductive load switching and diode recovery times

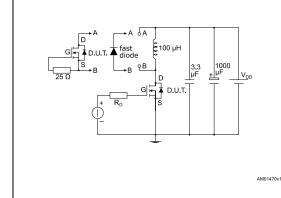


Figure 17: Unclamped inductive load test circuit

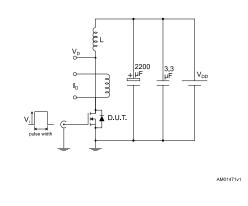


Figure 18: Unclamped inductive waveform

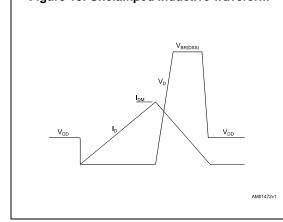
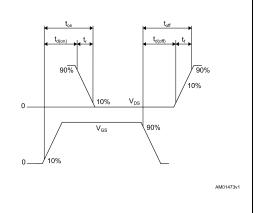


Figure 19: Switching time waveform



STD4N90K5 Package information

#### **Package information** 4

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

#### **DPAK** package information 4.1

THERMAL PAD <u>c</u>2 L2 <u>b(</u>2x) R SEATING PLANE (L1) 0,25 0068772\_A\_21

Figure 20: DPAK (TO-252) type A package outline

Table 10: DPAK (TO-252) type A mechanical data

	Table 10. DFAK (10-232) type A mechanical data					
Dim.		mm				
Dilli.	Min.	Тур.	Max.			
Α	2.20		2.40			
A1	0.90		1.10			
A2	0.03		0.23			
b	0.64		0.90			
b4	5.20		5.40			
С	0.45		0.60			
c2	0.48		0.60			
D	6.00		6.20			
D1	4.95	5.10	5.25			
Е	6.40		6.60			
E1	4.60	4.70	4.80			
е	2.16	2.28	2.40			
e1	4.40		4.60			
Н	9.35		10.10			
L	1.00		1.50			
(L1)	2.60	2.80	3.00			
L2	0.65	0.80	0.95			
L4	0.60		1.00			
R		0.20				
V2	0°		8°			

STD4N90K5 Package information

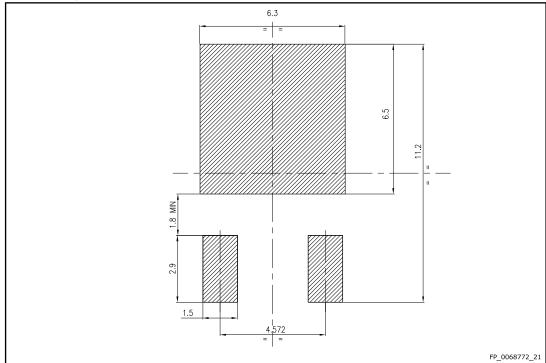


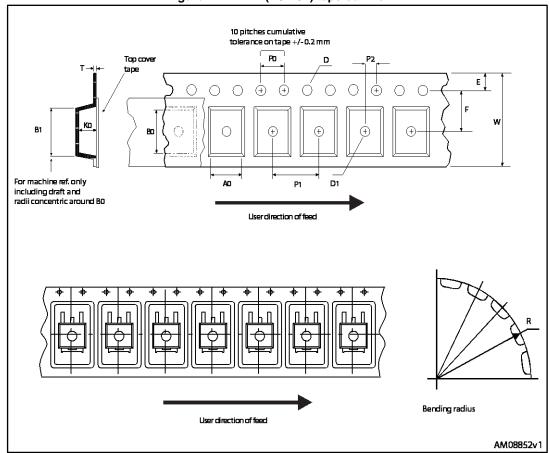
Figure 21: DPAK (TO-252) recommended footprint (dimensions are in mm)

Package information STD4N90K5

## 4.2 DPAK packing information

12/15

Figure 22: DPAK (TO-252) tape outline



A Tape slot in core for tape start 2.5mm min.width

AM06038v1

Figure 23: DPAK (TO-252) reel outline

Table 11: DPAK (TO-252) tape and reel mechanical data

Таре			Reel		
Dim.	mm		Dim	mm	
	Min.	Max.	Dim.	Min.	Max.
A0	6.8	7	А		330
B0	10.4	10.6	В	1.5	
B1		12.1	С	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
Е	1.65	1.85	N	50	
F	7.4	7.6	Т		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty. 2500		2500
P1	7.9	8.1	Bulk qty. 2500		2500
P2	1.9	2.1			
R	40				
Т	0.25	0.35			
W	15.7	16.3			

Revision history STD4N90K5

## 5 Revision history

14/15

**Table 12: Document revision history** 

Date	Revision	Changes
02-Nov-2016	1	First release.

#### **IMPORTANT NOTICE - PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2016 STMicroelectronics - All rights reserved

### **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for MOSFET category:

Click to view products by STMicroelectronics manufacturer:

Other Similar products are found below:

614233C 648584F IRFD120 JANTX2N5237 SPP20N60S5XK FCA20N60\_F109 FDZ595PZ 2SK2545(Q,T) 405094E 423220D

TPCC8103,L1Q(CM MIC4420CM-TR VN1206L SBVS138LT1G 614234A 715780A NTNS3166NZT5G SSM6J414TU,LF(T 751625C BUK954R8-60E DMN3404LQ-7 NTE6400 SQJ402EP-T1-GE3 2SK2614(TE16L1,Q) 2N7002KW-FAI DMN1017UCP3-7

EFC2J004NUZTDG ECH8691-TL-W FCAB21350L1 P85W28HP2F-7071 DMN1053UCP4-7 NTE221 NTE2384 NTE2903 NTE2941 NTE2945 NTE2946 NTE2960 NTE2967 NTE2969 NTE2976 NTE455 NTE6400A NTE2910 NTE2916 NTE2956 NTE2911 DMN2080UCB4-7 TK10A80W,S4X(S SSM6P69NU,LF